



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shendon et al. Art Unit : 3723  
Serial No. : 10/688,663 Examiner : George Binh Minh Nguyen  
Filed : October 16, 2003  
Title : FLUID-PRESSURE REGULATED WAFER POLISHING HEAD

**MAIL STOP AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents are enclosed. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed within three months of the filing date of the Request for Continued Examination or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 7/15/05

David J. Goren  
David J. Goren  
Reg. No. 34,609

Telephone: (650) 839-5070  
Facsimile: (650) 839-5071

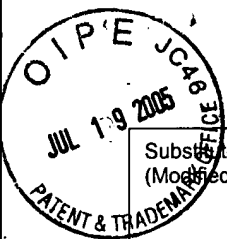
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I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Nikia M. Mc Nillion  
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Substitute Form PTO-1449  
(Modified)U.S. Department of Commerce  
Patent and Trademark OfficeAttorney's Docket No.  
05542-099006Application No.  
10/688,663**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

Applicant  
Shendon et al.Filing Date  
October 16, 2003Group Art Unit  
3723

(37 CFR §1.98(b))

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	JP 08-229808	09/1996	Japan			English Abstract	
	AM	JP 64-045566	02/1989	Japan			English Abstract	
	AN							
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
	AQ	Notice of Rejection, JP Application Serial No. 8-147597, June 21, 2005, 4 pp.
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.